

APPLICATIONS
OF
**ELECTRON
MICROFRACTOGRAPHY**
TO MATERIALS
RESEARCH

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AMERICAN SOCIETY FOR TESTING AND MATERIALS

APPLICATIONS OF ELECTRON MICROFRACTOGRAPHY TO MATERIALS RESEARCH

A symposium
presented at the
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Foreword

The Symposium on Applications of Electron Microfractography to Materials Research was given at the Seventy-third Annual Meeting of the American Society for Testing and Materials held in Toronto, Ont., Canada, 21-26 June 1970. The Sponsor of this symposium was ASTM Subcommittee II on Fractography and Associated Microstructures of ASTM Committee E-24 on Fracture Testing of Metals. W. Wiebe, National Research Council of Canada, presided as symposium chairman.

Related ASTM Publications

Fracture Toughness Testing and Its Applications,
STP 381 [1965], \$19.50

Electron Microfractography, STP 453 [1969], \$16.00

Review of Developments in Plane Strain Fracture
Toughness Testing, STP 463 [1970], \$18.25

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